

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re new PATENT application of )  
Hidekazu MIYAIRI et al. )  
Based on Japanese Patent No. 2003-085096 ) New Applications  
Filed: March 26, 2003 )  
For: METHOD FOR TESTING )  
SEMICONDUCTOR FILM, )  
SEMICONDUCTOR DEVICE AND )  
MANUFACTURING METHOD THEREOF )

**PRELIMINARY AMENDMENT**

Commissioner of Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Sir:

**Amendments to the Specification** begins on page 2 of this paper.

**Remarks** begin on page 3 of this paper.